

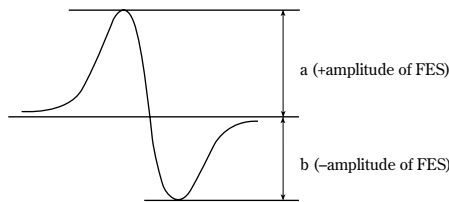
■ Electro-optical Characteristics

(T_c=25°C)

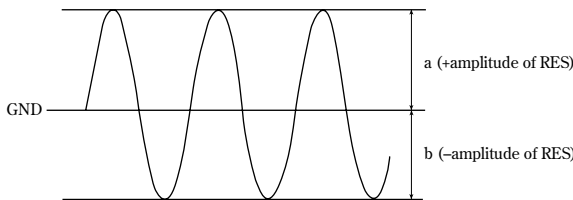
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
#1 Focal offset	DEF	Collimated lens output power 1.5mW, High gain	-0.7	-	+0.7	μm
#2 Focal error symmetry	B _{FES}	Collimated lens output power 1.5mW, High gain	-25	-	+25	%
#3 Radial error balance	B _{RES}	Collimated lens output power 1.5mW, High gain	-25	-	+25	%
#4 RF output amplitude	V _{RFH}	Collimated lens output power 1.5mW, High gain	0.65	1.0	1.6	V
#5 FES output amplitude	V _{FES}	Collimated lens output power 1.5mW, High gain	0.3	0.59	0.94	V
#6 RES output amplitude	V _{RES}	Collimated lens output power 1.5mW, High gain	0.09	0.19	0.3	V
#7 Main spot balance	MSB	Collimated lens output power 1.5mW, High gain	80	(100)	120	%
#8 Sub spot balance	SSB	Collimated lens output power 1.5mW, High gain	80	(100)	120	%
Jitter	JIT	Collimated lens output power 1.5mW, High gain	-	-	23	ns
#9 Strain of RF signal shape	RF _h	Collimated lens output power 1.5mW, High gain	-	-	300	%

#1 Distance between FES=0 and jitter minimum point

#2 $(a-b) / (a+b)$



#3 $\frac{a-b}{2 \times (a+b)}$



#4 Amplitude of V_A+V_B+V_C+V_D (focal servo ON, radial servo ON)

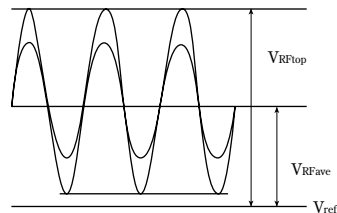
#5 V_B-V_A (Focal vibration)

#6 Amplitude of (V_C-V_D)-k₁(V_E+G-V_F+H). k₁=(V_C+V_D)/(V_E+G+V_F+H)=1
When tracking servo is ON, (V_C-V_D)-k₁(V_E+G-V_F+H)+α should be 0.

#7 (V_A+V_B) / (V_C+V_D)

#8 V_C/V_D

#9 V_{RFtop}/V_{RFave}



■ Electro-optical Characteristics of Laser Diode

(T_C=25°C)

Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit	
Threshold current		I _{th}	-	-	30	40	mA	
Operating current		I _{op}	Po=100mW	-	141	167	mA	
Operating voltage		V _{op}	Po=100mW	-	2.2	2.5	V	
Wavelength		λ _p	Po=100mW	773	784	797	nm	
Differential efficiency		η _d	$\frac{90\text{mW}}{I(100\text{mW})-I(10\text{mW})}$	0.75	0.9	1.15	mW/mA	
Stability of differential efficiency		Δη _d	Po=10 to 180mW	-	-	40	%	
Half intensity angle		Parallel	Po=100mW	8.0	9	10.2	°	
		Perpendicular		14.5	16.0	17.5	°	
Emission characteristics		Parallel		-2	-	+2	°	
		Perpendicular		-3	-	+3	°	
Beam shift		Δθ//		θ//(100mW)-θ//(3mW)	-1	-	+1	°
Kink		K-LI1		Po=10 to 180mW	0.988	-	-	%
		K-LI2	P1=36mW, P2=108mW, P3=180mW	-	-	15	%	

■ Electro-optical Characteristics of OPIC for Signal Detection^{*10}

(T_C=25°C, V_{CC}=5V, V_{ref}=2.1V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit	^{*11} Segment
Supply current	I _{CC1}	High gain, Gain switching SW=H	-	25	32	mA	
	I _{CC2}	Low gain, Gain switching SW=L	-	30	35	mA	
^{*12} Output offset voltage	V _{od}	Common to high/low gain, No light	-25	2	+25	mV	A, B
Offset voltage difference, Gain switching	ΔV _{od}	Common to high/low gain	-30	-	+30	mV	A, B

^{*9} 0.1μF or more capacitor should be added between OPIC power supply terminal and GND, V_{ref} terminal and GND. (at the position of 10mm or less from the lead base)

^{*10} Applicable divisions correspond to output terminals .

A : V_A, V_B, V_C, V_D

B : V_{E+G}, V_{F+H}

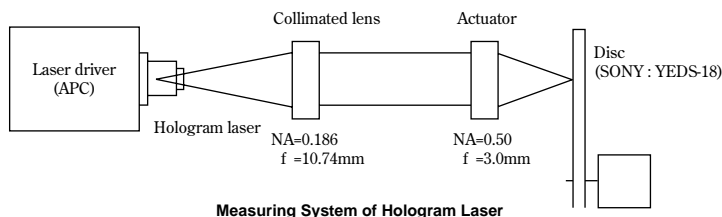
^{*11} Difference from V_{ref}

■ Electro-optical Characteristics of Hologram Laser (Design Standard*)^{*1}

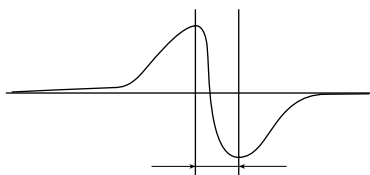
(T_C=25°C)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
^{*2} Focal error signal capture range	-	-	-	14	-	μm
Focal error signal sensitivity	-	-	-	13	-	%/μm

^{*1}



^{*2}



* These parameters are not guaranteed performance, but general specifications of each optical element which makes up a hologram laser.

■ Optical Characteristics of Hologram Device (Design Standard*)

(T_C=25°C)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Hologram diffraction efficiency	0 th	$\lambda=780\text{nm}$	(79)	(83)	-	%
	$\pm 1\text{st}$		(5.5)	(6.9)	(8.5)	%
Hologram diffraction angle	D1, D2	$\lambda=780\text{nm}$	-	20.7	-	°
	Except D1, D2		-	26.3	-	°
Grating diffraction efficiency	-	0:1	6.7	9	12.4	-
Grating diffraction angle	-	$\lambda=780\text{nm}$	-	2.72	-	°

■ Electro-optical Characteristics of Laser Diode (Design Standard*)

(T_C=25°C)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Misalignment position	Δx	-	-80	-	+80	μm
	Δy		-80	-	+80	μm
	Δz		-80	-	+80	μm
*3 Reflectivity of LD rear facet	R _r	-	85	-	-	%

■ Electro-optical Characteristics of OPIC for Signal Detection (Design Standard*)

(T_C=25°C, V_{CC}=5V, V_{ref}=2.1V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit	*4 Segment
Supply voltage	V _{CC}	-	4.5	5	5.5	V	
Reference voltage	V _{ref}	-	2.00	2.1	2.21	V	
Output terminal current	I _o	Common to high/low gain	-0.03	0.01	0.3	mA	A, B
Reference voltage terminal current	I _{ref}	Common to high/low gain, No light	-0.5	1	2	mA	
*6,7,8,9 Response frequency	f _{cm}	Main amp, Common to high/low gain, -3dB	45	60	-	MHz	A
	f _{cs}	Sub amp, Common to high/low gain, -3dB	1	2	-	MHz	B
*5,6,8,9 Peaking level	V _{pk2}	Common to high/low gain f=0.1 to 45MHz	-	-	3	dB	A
*9 Noise level	f _{nm}	Hign gain, 50 Ω end BW=30kHz, f=36MHz	-	-74	-68	dBm	A
Sensitivity 1	R _{m1}	Main amp, Hign gain	18	24	30	mV/ μW	A
Sensitivity 2	R _{m2}	Main amp, Low gain	0.72	0.96	1.2	mV/ μW	A
Sensitivity 3	R _{m3}	Sub amp, Hign gain	72	96	120	mV/ μW	B
Sensitivity 4	R _{m4}	Sub amp, Low gain	2.88	3.84	4.8	mV/ μW	B
Thermal drift of sensitivity	R _{sm} /T	Common to high/low gain	-	4 200	-	ppm/°C	A, B
Thermal drift of offset voltage	V _{od} /T	Common to high/low gain, No light	-	300	-	$\mu\text{V}/^\circ\text{C}$	A, B
Thermal drift of offset voltage 1	V _{os1} /T	Main amp, Hign gain, No light	-	30	-	$\mu\text{V}/^\circ\text{C}$	A
Thermal drift of offset voltage 2	V _{os2} /T	Main amp, Low gain, No light	-	15	-	$\mu\text{V}/^\circ\text{C}$	A
Thermal drift of offset voltage 3	V _{os3} /T	Sub amp, Hign gain, No light	-	30	-	$\mu\text{V}/^\circ\text{C}$	B
Thermal drift of offset voltage 4	V _{os4} /T	Sub amp, Low gain, No light	-	15	-	$\mu\text{V}/^\circ\text{C}$	B
Thermal drift of offset voltage 5	V _{os5} /T	Between main-sub amp, Hign gain, No light	-	100	-	$\mu\text{V}/^\circ\text{C}$	A-B
Thermal drift of offset voltage 6	V _{os6} /T	Between main-sub amp, Low gain, No light	-	45	-	$\mu\text{V}/^\circ\text{C}$	A-B
Over/undershoot at gain switching	t _{str1}	Common to high/low gain, Integral value of the first overshoot/undershoot peak value and overshoot/undershoot time	-	200	-	$\mu\text{s} \times \text{mV}$	A, B
Stabilization time at gain switching	t _{str2}	Common to high/low gain, time for $\pm 3\text{mV}$	-	-	25	μs	A, B
Settling time	t _{est}	Output voltage 500mV \rightarrow 5mV Low gain, fall time	f=6.9MHz	30	-	ns	A
Maximum output voltage	V _{omax}	Common to high/low gain, V _{ref} reference	1	-	-	V	A, B

*3 Sampling rate is 1pc./reflection membrane formation process lot

*4 Applicable divisions correspond to output terminals.

A : V_A, V_B, V_C, V_D

B : V_{E+G}, V_{F+H}

*5 Difference from V_{ref}

*6 Light source is a laser diode of $\lambda=780\text{nm}$.

*7 -3dB level (0dB level is taken for output level when f=0.1MHz)

*8 10 μW of DC light is applied to the center of each photodiode, and 4 μW of AC light is irradiated. BW=10kHz

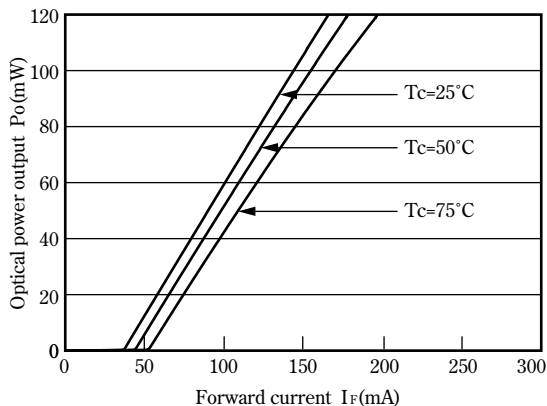
*9 5k Ω of resistor and 10pF of capacitor should be connected in parallel between output terminal and V_{ref} terminal.

* These parameters are not guaranteed performance, but general specifications of each optical element which makes up a hologram laser.

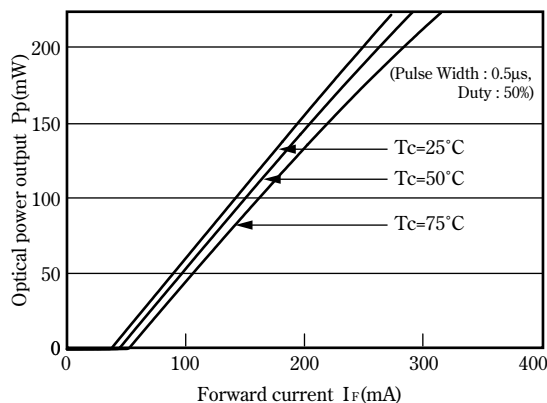
• Please refer to the chapter "Handling Precautions"

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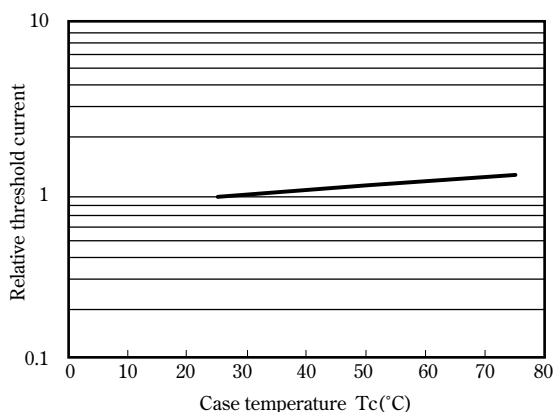
Optical power output - Forward current [CW]



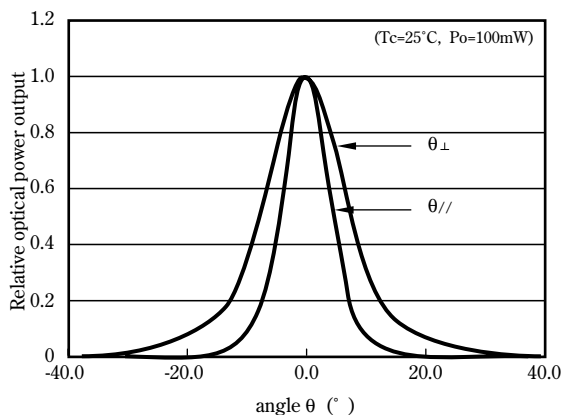
Optical power output - Forward current [Pulse]



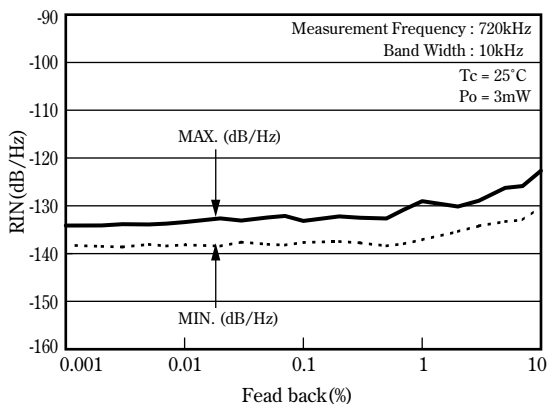
Case temperature dependence of threshold current [CW]



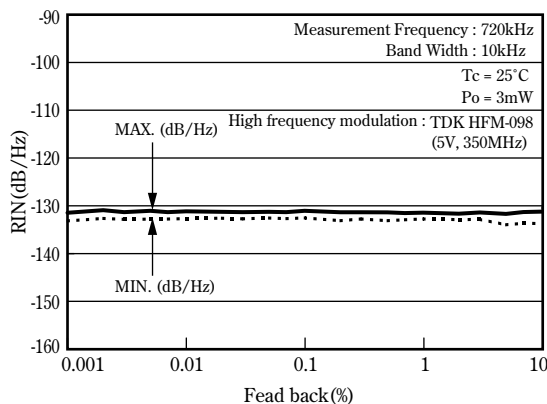
Far field pattern



Relative intensity noise (RIN) [without high frequency modulation]

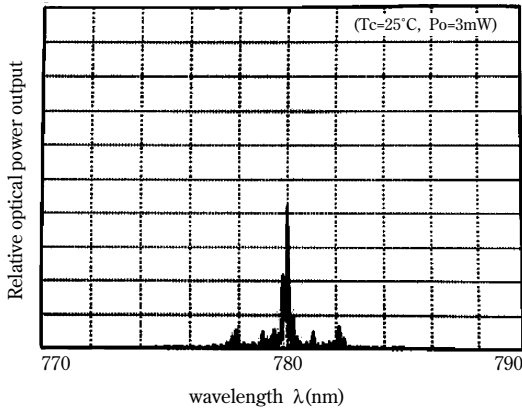


Relative intensity noise (RIN) [with high frequency modulation]

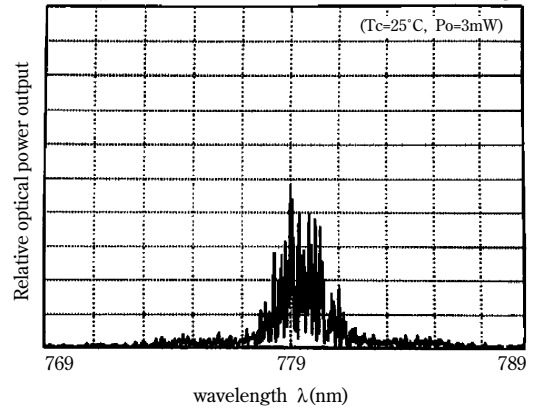


Note) Characteristics shown in diagrams are typical values. (not assurance value)

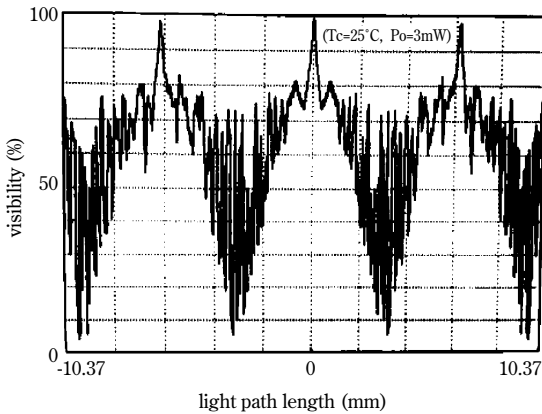
Lasing spectrum [without high frequency modulation]



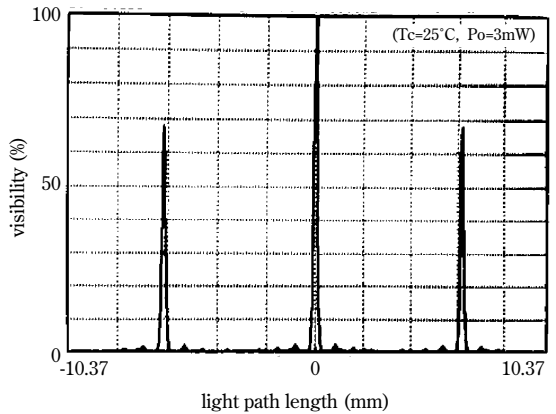
Lasing spectrum [with high frequency modulation]



Visibility [without high frequency modulation]



Visibility [with high frequency modulation]



Note) Characteristics shown in diagrams are typical values. (not assurance value)

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